PATENT NUMBER and ISSUE DATE

U.S. UTILITY Pat nt Application

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	APPL NUM	FILING DATE	CLASS	SUBCLASS	GAU	EXAMINER						
۱	10078240	02/20/2002	438	i'	1702	- · · · · ·						
	**APPLICANT	*APPLICANTS: Yamazaki Shunpei; Mitsuki Toru; Takano Tamae;										
	*CONTINUING DATA VERIFIED:											
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	** FOREIGN APPLICATIONS VERIFIED:											
	JAPAN 2001-049468 02/23/2001											
	PG-PUB DO	NOT PUBLISH	3	RESC	IND 🗆							
	Foreign priority o	reign priority claimed ☐ yes ☐ no ATTORNEY DOCKET		ATTORNEY DOCKET NO								
	35 USC 119 conditions met ☐ yes ☐ no Verified and Acknowledged Examiners's initials 740756-2438					740756-2438						
•	TITLE: Method of manufacturing a semiconductor device											

NOTICE OF ALL	OWANCE MAILED		CLAIMS ALLOWED					
		Assistant Examiner	Total Claims		Print Claim for O.G			
1991	UE FEE		DRAWING					
Amount Due	Date Pald	1	Sheets Drwg.	Figs.Drwg.	Print Fig.			
		Primary Examiner						
TEI	RMINAL	PREPARED FOR ISSUE	Applicati n Examiner					
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